May 1996



# NDP7060 / NDB7060 N-Channel Enhancement Mode Field Effect Transistor

#### **General Description**

Features

These N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, high cell density, DMOS technology. This very high density process is especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulses in the avalanche and commutation modes. These devices are particularly suited for low voltage applications such

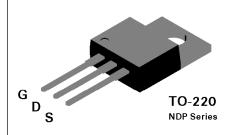
as automotive, DC/DC converters, PWM motor controls, and

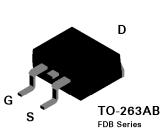
other battery powered circuits where fast switching, low in-line

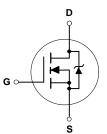
power loss, and resistance to transients are needed.

- 75A, 60V. R<sub>DS(ON)</sub> = 0.013Ω @ V<sub>GS</sub>=10V.
  Critical DC electrical parameters specified at elevated
  - temperature.

    Rugged internal source-drain diode can eliminate the need
  - for an external Zener diode transient suppressor.
  - 175°C maximum junction temperature rating.
  - High density cell design for extremely low R<sub>DS(ON)</sub>.
  - TO-220 and TO-263 (D<sup>2</sup>PAK) package for both through hole and surface mount applications.







#### **Absolute Maximum Ratings** T<sub>c</sub> = 25°C unless otherwise noted

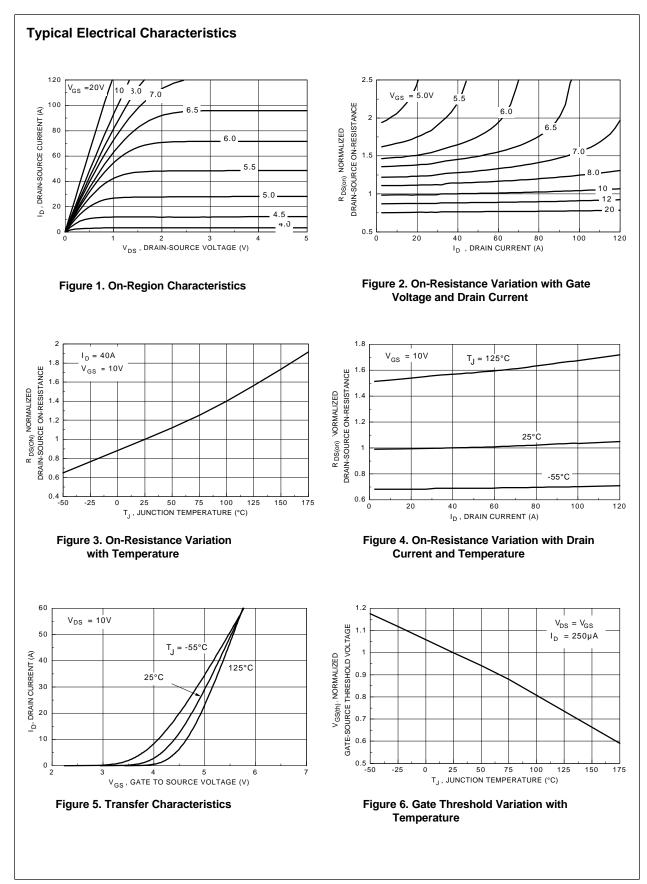
Symbol	Parameter	NDP7060	NDB7060	Units
/ <sub>DSS</sub>	Drain-Source Voltage	60		V
/ <sub>DGR</sub>	Drain-Gate Voltage ( $R_{GS} \le 1 \text{ M}\Omega$ )	60	V	
V <sub>GSS</sub>	Gate-Source Voltage - Continuous	±20		V
	- Nonrepetitive ( $t_p < 50 \ \mu s$ )	±40		
I <sub>D</sub>	Drain Current - Continuous	75		А
	- Pulsed	225		
P <sub>D</sub>	Maximum Power Dissipation @ $T_c = 25^{\circ}C$	150		W
	Derate above 25°C	1		W/°C
J,T <sub>STG</sub>	Operating and Storage Temperature Range	-65 to 2	175	°C
L	Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds	275		°C

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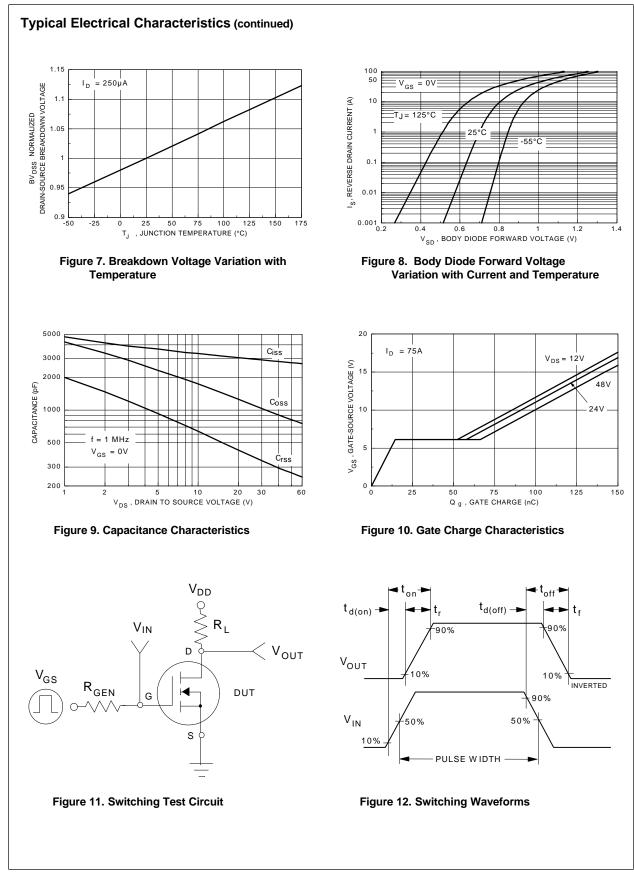
Symbol	Parameter	Conditions		Min	Тур	Max	Units
DRAIN-S	OURCE AVALANCHE RATINGS (Note 1)						
W <sub>DSS</sub>	Single Pulse Drain-Source Avalanche Energy	$V_{DD} = 25 \text{ V}, \text{ I}_{D} = 75 \text{ A}$				550	mJ
I <sub>AR</sub>	Maximum Drain-Source Avalanche Curre	ent				75	А
OFF CH/	ARACTERISTICS						
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_{D} = 250 \ \mu\text{A}$		60			V
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	$V_{DS} = 60 \text{ V}, \text{ V}_{GS} = 0 \text{ V}$				250	μA
			T <sub>J</sub> = 125°C			1	mA
GSSF	Gate - Body Leakage, Forward	$V_{GS} = 20 \text{ V}, V_{DS} = 0 \text{ V}$	·			100	nA
GSSR	Gate - Body Leakage, Reverse	$V_{GS} = -20 \text{ V}, \text{ V}_{DS} = 0 \text{ V}$				-100	nA
ON CHAI	RACTERISTICS (Note 1)	·					
V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$		2	2.8	4	V
00(0)			T <sub>J</sub> = 125°C	1.4	2.1	3.6	1
R <sub>DS(ON)</sub>	Static Drain-Source On-Resistance	$V_{GS} = 10 \text{ V}, \text{ I}_{D} = 40 \text{ A}$			0.01	0.013	Ω
			T <sub>J</sub> = 125°C		0.015	0.024	
D(on)	On-State Drain Current	$V_{GS} = 10 \text{ V}, V_{DS} = 10 \text{ V}$		75			А
9 <sub>FS</sub>	Forward Transconductance	V <sub>DS</sub> = 10 V, I <sub>D</sub> = 37.5 A		15	39		S
DYNAMI	C CHARACTERISTICS						
C <sub>iss</sub>	Input Capacitance	$V_{DS} = 25 V, V_{GS} = 0 V,$ f = 1.0 MHz			2960	3600	pF
C <sub>oss</sub>	Output Capacitance				1130	1600	pF
C <sub>rss</sub>	Reverse Transfer Capacitance				380	800	pF
	NG CHARACTERISTICS (Note 1)			1	1		
t <sub>D(on)</sub>	Turn - On Delay Time	$V_{DD} = 30 \text{ V}, \ \text{I}_{D} = 75 \text{ A},$			17	30	nS
tr	Turn - On Rise Time	$\rm V_{GS}$ = 10 V, $\rm R_{GEN}$ = 5 $\Omega$			128	400	nS
t <sub>D(off)</sub>	Turn - Off Delay Time	-			54	80	nS
f	Turn - Off Fall Time				90	200	nS
<u> </u>	Total Gate Charge	V <sub>DS</sub> = 48 V,			100	115	nC
Q <sub>gs</sub>	Gate-Source Charge	$V_{DS} = 46 \text{ V},$ $I_{D} = 75 \text{ A}, V_{GS} = 10 \text{ V}$			14.5		nC
Q <sub>gd</sub>	Gate-Drain Charge				51		nC

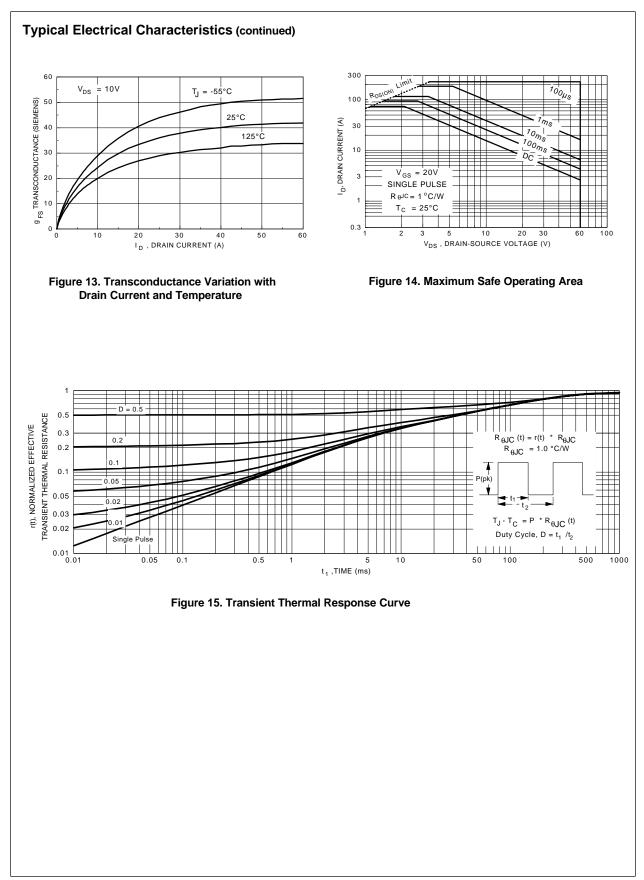
Electric	al Characteristics (T <sub>c</sub> = 25°C unless o	therwise noted)					
Symbol	Parameter	Conditions		Min	Тур	Max	Units
DRAIN-S	OURCE DIODE CHARACTERISTICS						
I <sub>s</sub>	Maximum Continuos Drain-Source Diode Forward Current				75	А	
I <sub>SM</sub>	Maximum Pulsed Drain-Source Diode Forward Current				225	А	
V <sub>SD</sub>	Drain-Source Diode Forward Voltage	$V_{GS} = 0 \text{ V}, \text{ I}_{S} = 37.5 \text{ A} (\text{Note 1})$			0.9	1.3	V
			T <sub>J</sub> = 125°C		0.84	1.2	
t <sub>r</sub>	Reverse Recovery Time	$V_{GS} = 0 \text{ V}, I_F = 75 \text{ A}, dI_F/dt = 100 \text{ A}$	μs	40	76	150	ns
I <sub>m</sub>	Reverse Recovery Current			2	4.7	10	А
THERMA	L CHARACTERISTICS						
R <sub>θJC</sub>	Thermal Resistance, Junction-to-Case					1	°C/W
R <sub>øja</sub>	Thermal Resistance, Junction-to-Ambient					62.5	°C/W
Note:	•				•	•	

1. Pulse Test: Pulse Width  $\leq$  300 µs, Duty Cycle  $\leq$  2.0%.



NDP7060.SAM





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